

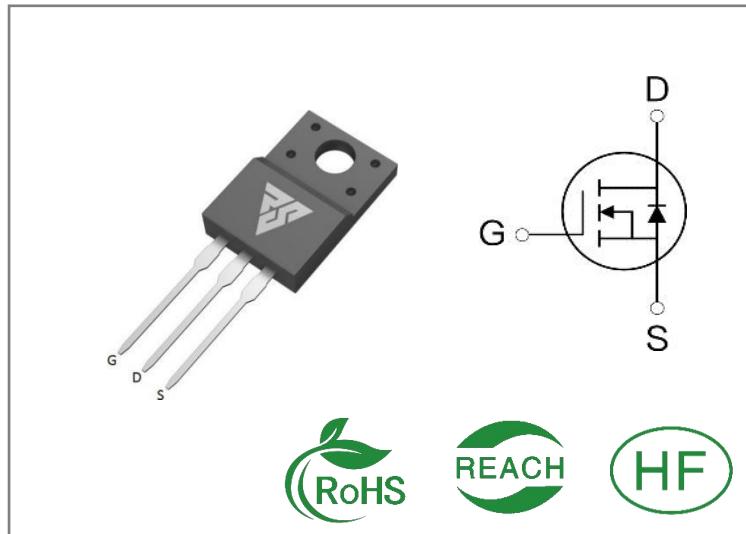
ID	R <sub>DS(ON)</sub> (Typ)	V <sub>DSS</sub>
13A	0.36Ω	500V

**Applications:**

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)

**Features:**

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability


**Ordering Information**

Part Number	Package	Marking	Packing	Qty.
RS13N50CF	TO-220F	RS13N50CF	Tube	50 PCS

**Absolute Maximum Ratings T<sub>c</sub> = 25°C unless otherwise specified**

Symbol	Parameter	RS13N50CF	Units
V <sub>DSS</sub>	Drain-to-Source Voltage	500	V
ID	Continuous Drain Current T <sub>C</sub> =25°C	13	A
	Continuous Drain Current T <sub>C</sub> =100°C	7.5	
IDM	Pulsed Drain Current (Note*1)	50	
PD	Power Dissipation	105	W
V <sub>GS</sub>	Gate- to- Source Voltage	±30	V
EAS	Single Pulse Avalanche Energy L = 10mH, V <sub>DD</sub> = 50V, R <sub>G</sub> = 25 Ω	700	mJ
TL TPKG	Maximum Temperature for Soldering	300 260	°C
	Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds		
T <sub>J</sub> and T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to 150	

\* Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the " Absolute Maximum Ratings" Table may cause permanent damage to the device.

**Thermal Resistance**

Symbol	Parameter	RS13N50CF	Units	Test Conditions
R <sub>θJC</sub>	Junction-to-Case	1.14	°C / W	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of + 150 °C
R <sub>θJA</sub>	Junction-to-Ambient	50		1 cubic foot chamber, free air.

**OFF Characteristics** TJ= 25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BVDSS	Drain- to- source Breakdown Voltage	500	--	--	V	V <sub>GS</sub> =0V, ID=250μA
IDSS	Drain- to- Source Leakage Current	--	--	1	μA	V <sub>DS</sub> =500V, V <sub>GS</sub> =0V
IGSS	Gate- to- Source Forward Leakage	--	--	100	nA	V <sub>GS</sub> =30V, V <sub>DS</sub> =0V
	Gate- to- Source Reverse Leakage	--	--	-100		V <sub>GS</sub> =-30V, V <sub>DS</sub> =0V

**ON Characteristics** TJ=25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
R <sub>D(on)</sub>	Static Drain- to- Source On-Resistance (Note*2)	--	0.36	0.46	Ω	V <sub>GS</sub> =10V, ID=6.5A
V <sub>GS(TH)</sub>	Gate Threshold Voltage	2	--	4	V	V <sub>GS</sub> =V <sub>DS</sub> ID=250μA

**Resistive Switching Characteristics** Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
td(ON)	Turn- on Delay Time	--	29	--	nS	V <sub>DS</sub> =250V ID=13A RG=25Ω
trise	Rise Time	--	58	--		
td(OFF)	Turn- OFF Delay Time	--	58	--		
tfall	Fall Time	--	13	--		

**Dynamic Characteristics** Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
C <sub>iss</sub>	Input Capacitance	--	2050	--	pF	V <sub>GS</sub> =0V V <sub>DS</sub> =25V f=1.0MHz
C <sub>oss</sub>	Output Capacitance	--	182	--		
C <sub>rss</sub>	Reverse Transfer Capacitance	--	10	--		
Q <sub>g</sub>	Total Gate Charge	--	43	--	nC	V <sub>DS</sub> =400V I <sub>D</sub> =13A V <sub>GS</sub> =10V
Q <sub>gs</sub>	Gate- to- Source Charge	--	9	--		
Q <sub>gd</sub>	Gate-to-Drain(" Miller") Charge	--	16	--		

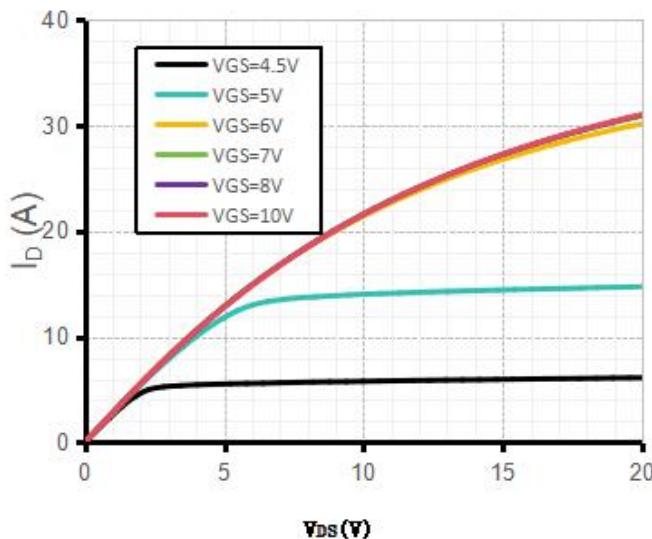
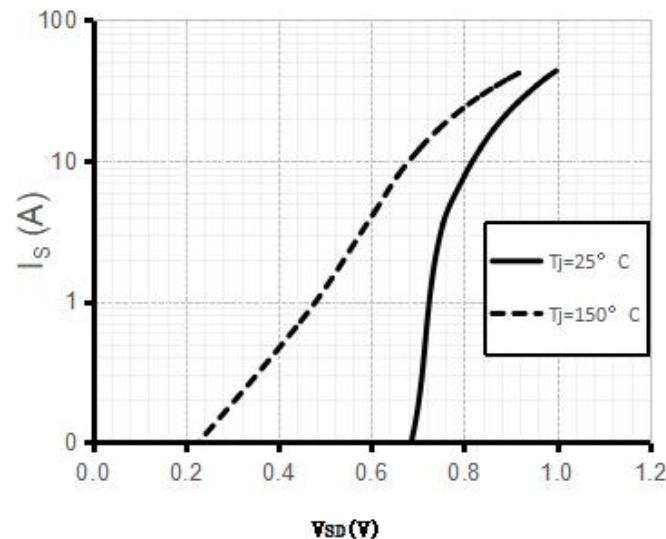
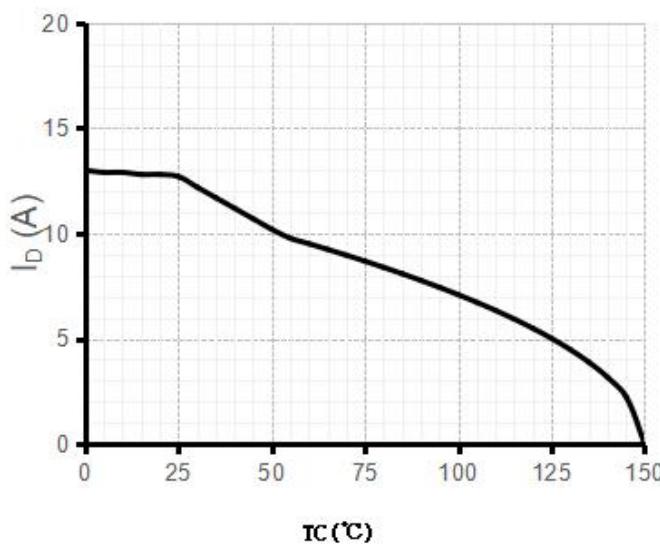
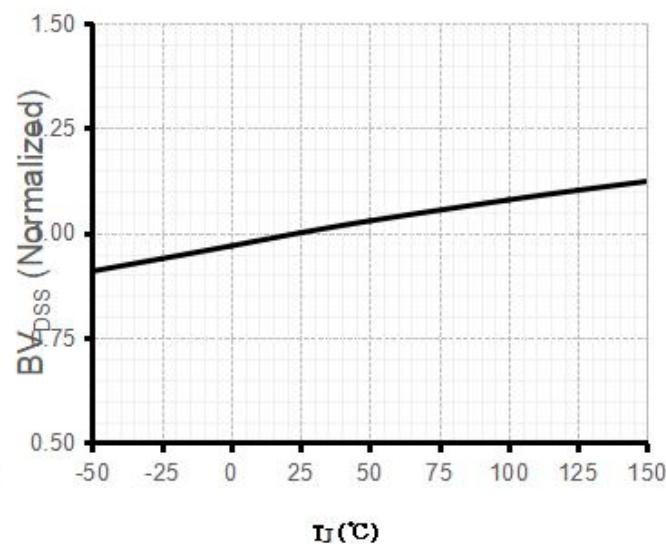
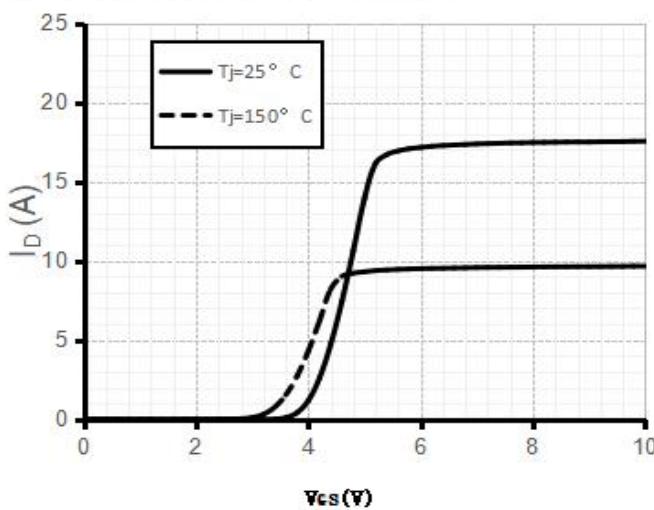
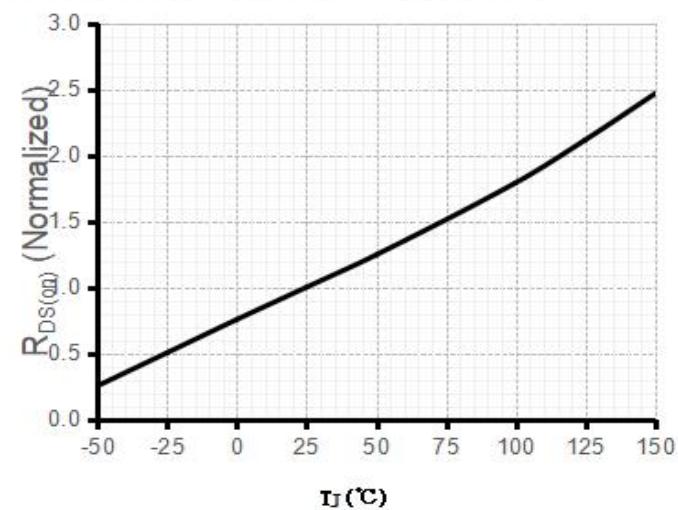
**Source- Drain Diode Characteristics**

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I <sub>S</sub>	Continuous Source Current	--	--	13	A	Integral pn- diode in MOSFET
I <sub>SM</sub>	Maximum Pulsed Current	--	--	50	A	
V <sub>SD</sub>	Diode Forward Voltage	--	0.8	1.2	V	I <sub>S</sub> =6.5A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	--	420	--	nS	V <sub>GS</sub> =0V I <sub>S</sub> =13A, di/dt=100A/μs
Q <sub>rr</sub>	Reverse Recovery Charge	--	4.4	--	μC	

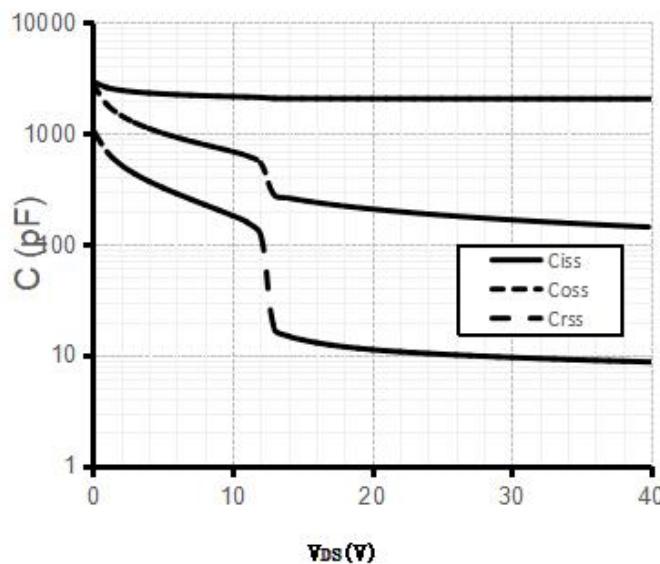
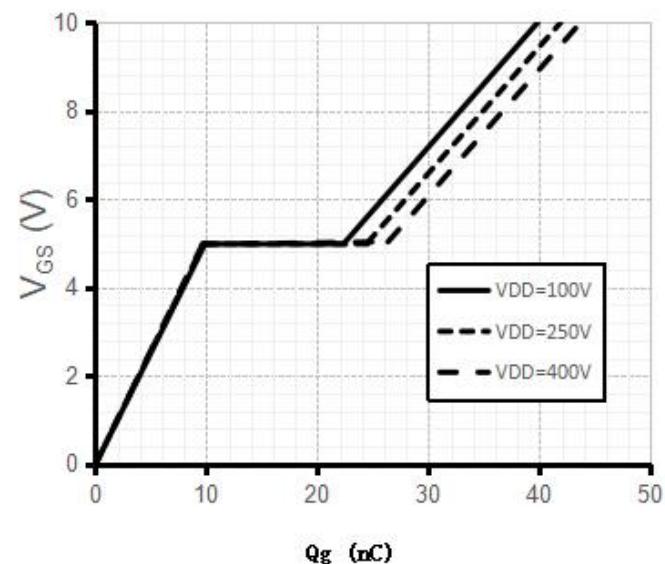
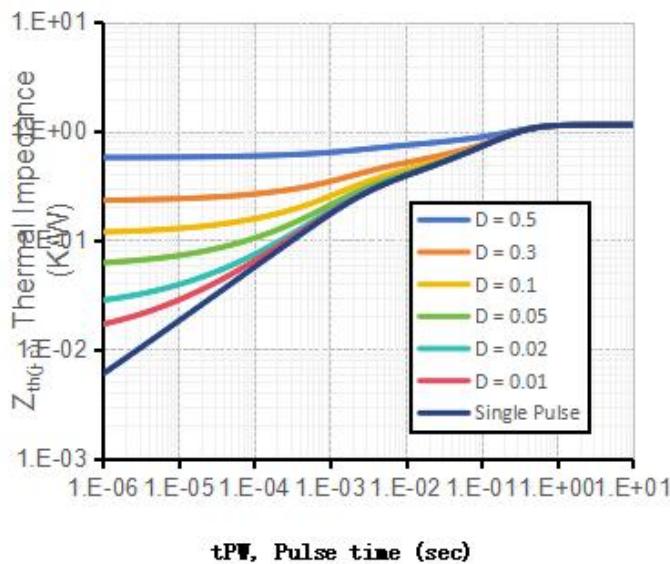
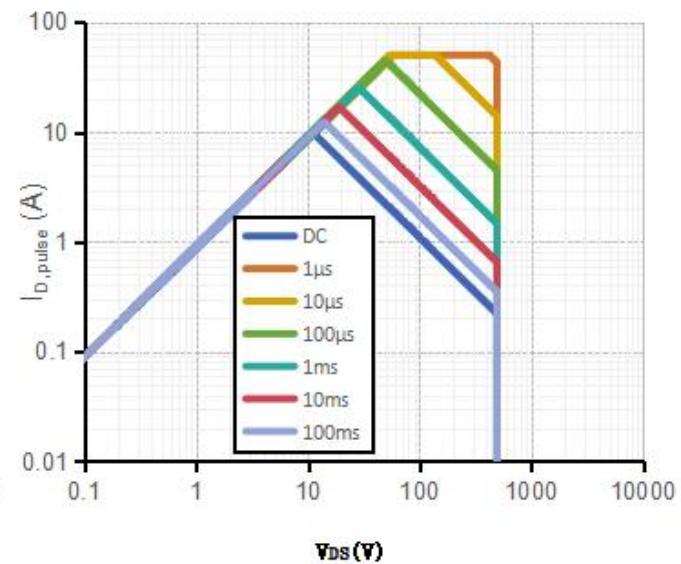
**Notes:**

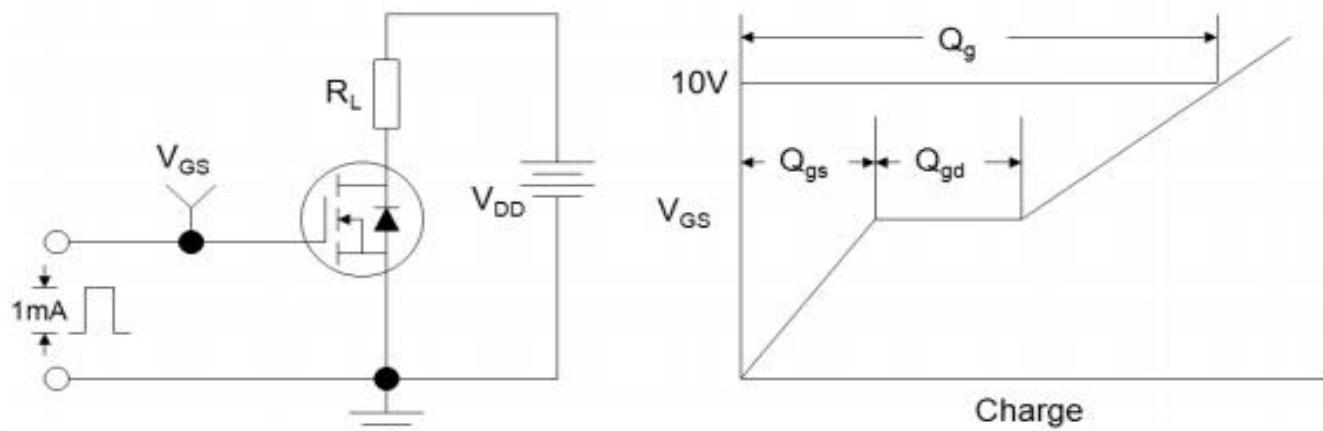
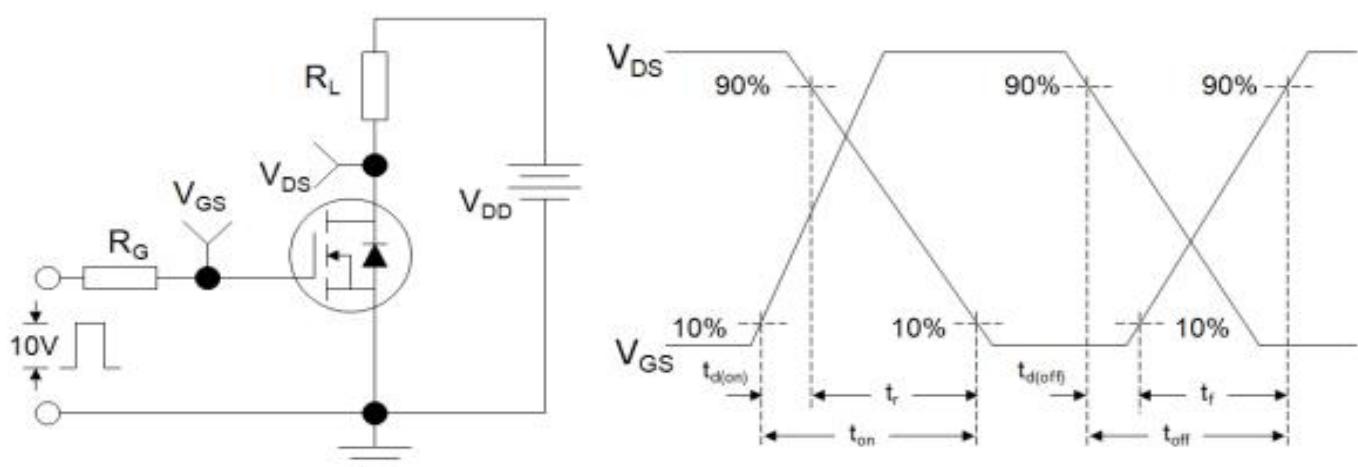
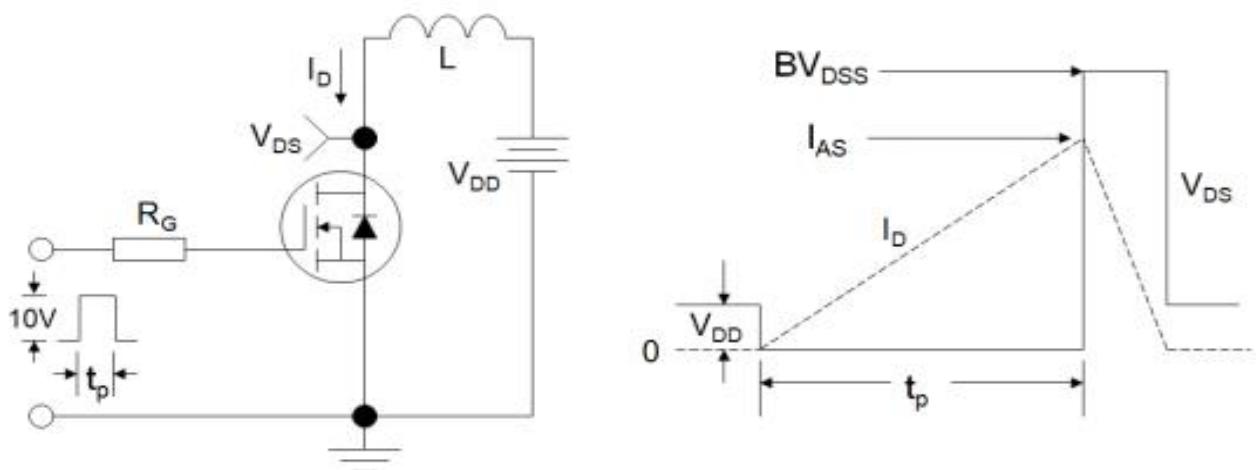
- \* 1. Repetitive rating,pulse width limited by maximum junction temperature.
- \* 2. Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%

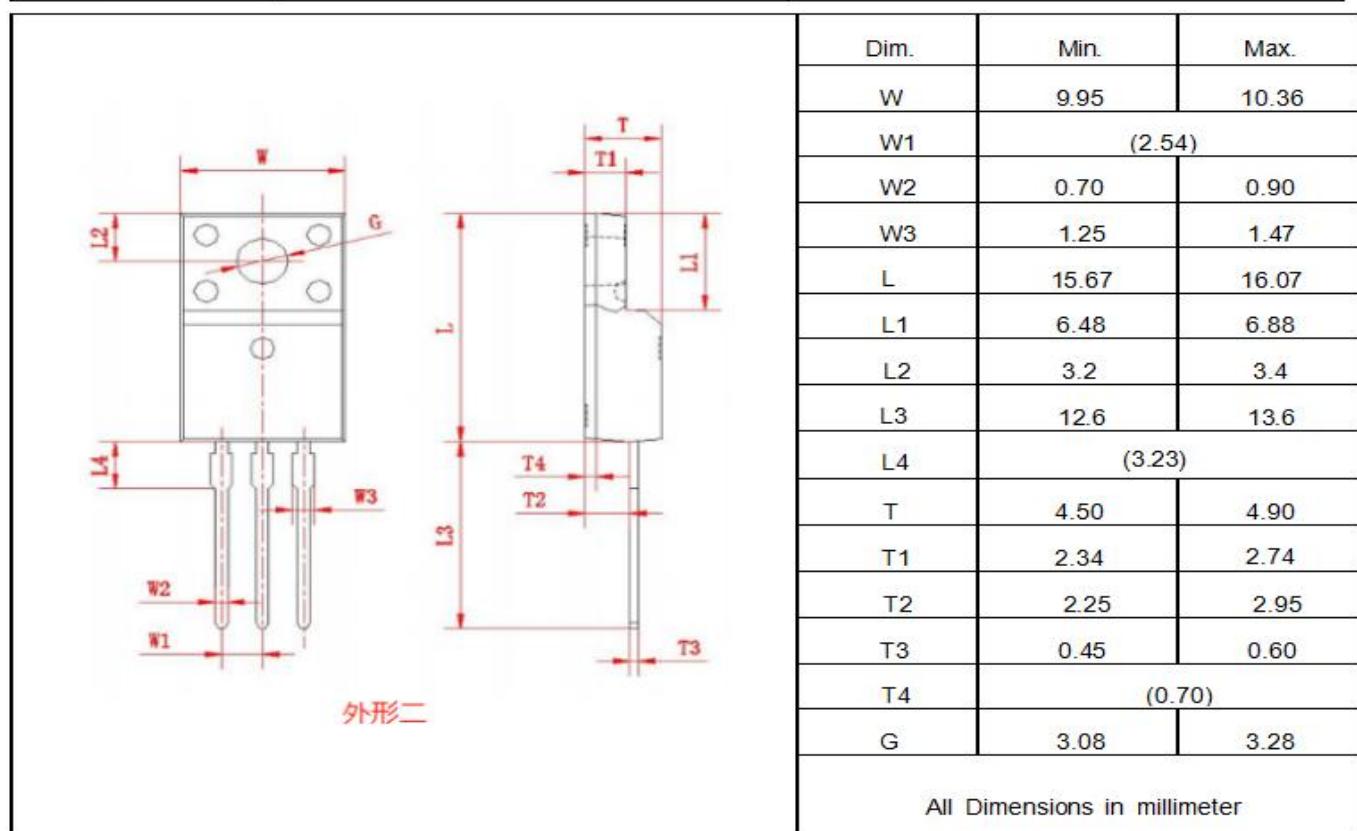
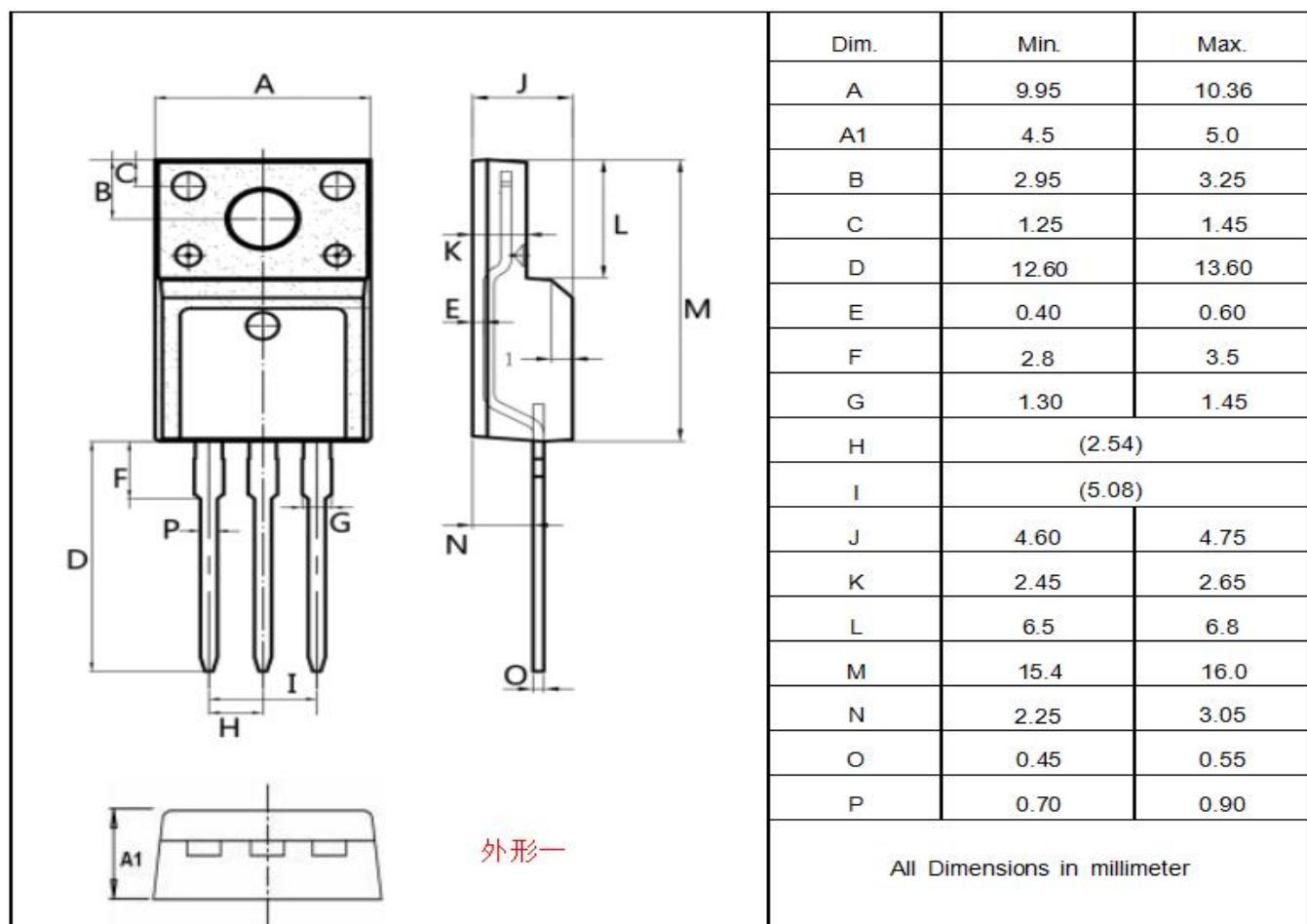
### Typical Feature Curve

**Figure 1. Output Characteristics (T<sub>j</sub>=25° C)**

**Figure 2. Body Diode Forward Voltage**

**Figure 3. Drain Current vs. Temperature**

**Figure 4. BV<sub>DSS</sub> Variation vs. Temperature**

**Figure 5. Transfer Characteristics**

**Figure 6. On-Resistance vs. Temperature**


### Typical Feature Curve

**Figure 7. Capacitance**

**Figure 8. Gate Charge**

**Figure 9. Transient Thermal Impedance**

**Figure 10. Safe Operating Area**


**Test Circuits and Waveforms**
**Figure A: Gate Charge Test Circuit and Waveform**

**Figure B: Resistive Switching Test Circuit and Waveform**

**Figure C: Unclamped Inductive Switching Test Circuit and Waveform**


**Package outline drawing (TO-220F Unit: mm)**


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